

<b>Notice of References Cited</b>	Application/Control No. 10/650,190	Applicant(s)/Patent Under Reexamination CIVLIN, JAN	
	Examiner Todd Ingberg	Art Unit 2193	Page 1 of 1

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**NON-PATENT DOCUMENTS**

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	U	Dynamic Trace Selection Using Performance monitoring Hardware Sampling, IEEE, Howard Chen et al, March 2003, pages 79 - 90
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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